

Title (en)  
CONNECTION DEVICE AND AUTOMATED SYSTEM FOR INSPECTING SPECIMEN

Title (de)  
VERBUNDUNGSVORRICHTUNG UND AUTOMATISIERTES SYSTEM ZUR UNTERSUCHUNG VON PROBEN

Title (fr)  
DISPOSITIF DE RACCORDEMENT ET SYSTÈME AUTOMATISÉ POUR INSPECTER UN SPÉCIMEN

Publication  
**EP 4053566 A4 20231108 (EN)**

Application  
**EP 20880547 A 20201021**

Priority  
• JP 2019198073 A 20191031  
• JP 2020039530 W 20201021

Abstract (en)  
[origin: EP4053566A1] Provided are: a connection device with which it is possible to improve the degree of freedom in positioning of an analysis device that analyzes a specimen; and an automated system for inspecting a specimen, the system comprising the connection device. A connection device for connecting a specimen transport device that transports a specimen container in which a specimen is accommodated and an analysis device that analyzes the specimen, the connection device being characterized by comprising: a carousel that transports a specimen carrier, on which the specimen container is placed, during a prescribed interval; a grip part positioned inside the carousel, the grip part gripping the specimen container at a specimen collection position, which is a position at which the specimen is collected; and a housing that covers the carousel, the connection device also being characterized in that the specimen collection position is above the transport path of the carousel and is positioned within a prescribed distance from the housing.

IPC 8 full level  
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CPC (source: CN EP US)  
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Citation (search report)  
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• [Y] US 2008271546 A1 20081106 - MILLER KERRY LYNN [US], et al  
• [A] US 2019265261 A1 20190829 - YAMAGUCHI SHIGEKI [JP], et al  
• [A] EP 0916952 A2 19990519 - BAYER AG [US]  
• See also references of WO 2021085264A1

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DOCDB simple family (publication)  
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**EP 20880547 A 20201021**; CN 202080065004 A 20201021; JP 2020039530 W 20201021; JP 2021553489 A 20201021; US 202017768736 A 20201021